

AM4924N-T1-PF-VB Datasheet DualN-Channel20-V(D-S)MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A)	Q _g (Typ.)			
20	0.009 at V _{GS} = 4.5 V	10	15 nC			
20	0.012 at V _{GS} = 2.5 V	8.0	15 NC			

SO-8 D_1 D_2

Top View

FEATURES

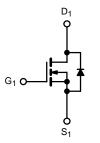
- Halogen-free According to IEC 61249-2-21 Definition
- TrenchFET® Power MOSFET
- 100 % UIS Tested
- 100 % R_q Tested
- Compliant to RoHS Directive 2002/95/EC

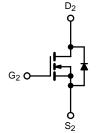


COMPLIANT HALOGEN **FREE**

APPLICATIONS

- Set Top Box
- Low Current DC/DC





N-Channel MOSFET

N-Channel MOSFET

Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V _{DS}	20	V	
Gate-Source Voltage		V _{GS}	± 12	V	
	T _C = 25 °C		10 ^a		
Continuous Drain Current (T _J = 150 °C)	$T_C = 70 ^{\circ}\text{C}$ $T_A = 25 ^{\circ}\text{C}$	I _D	7.0 8.1 ^{b, c}		
	T _A = 70 °C		7.2 ^{b, c}	Α Α	
Pulsed Drain Current		I _{DM}	44		
Continuous Source-Drain Diode Current	T _C = 25 °C	Is	3.25		
	T _A = 25 °C	o o	1.88 ^{b, c}		
Single Pulse Avalanche Current	L = 0.1 mH	I _{AS}	6		
Single Pulse Avalanche Energy	L=0.11IIII	E _{AS}	1.45	mJ	
	T _C = 25 °C		2.7		
Maximum Power Dissipation	T _C = 70 °C	P_{D}	1.77	w	
Maximum r ower Dissipation	$T_A = 25 ^{\circ}C$] , ,	1.78 ^{b, c}	VV	
	T _A = 70 °C] [1.14 ^{b, c}		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS							
Parameter		Symbol	Typical	Maximum	Unit		
Maximum Junction-to-Ambient ^{a, c, d}	t ≤ 10 s	R _{thJA}	58	70	°C/W		
Maximum Junction-to-Foot (Drain)	Steady State	$R_{th,IF}$	38	45	J 5/VV		

Notes:

- a. Package limited, T_C = 25 °C.
 b. Surface Mounted on 1" x 1" FR4 board.
- d. Maximum under Steady State conditions is 110 °C/W.



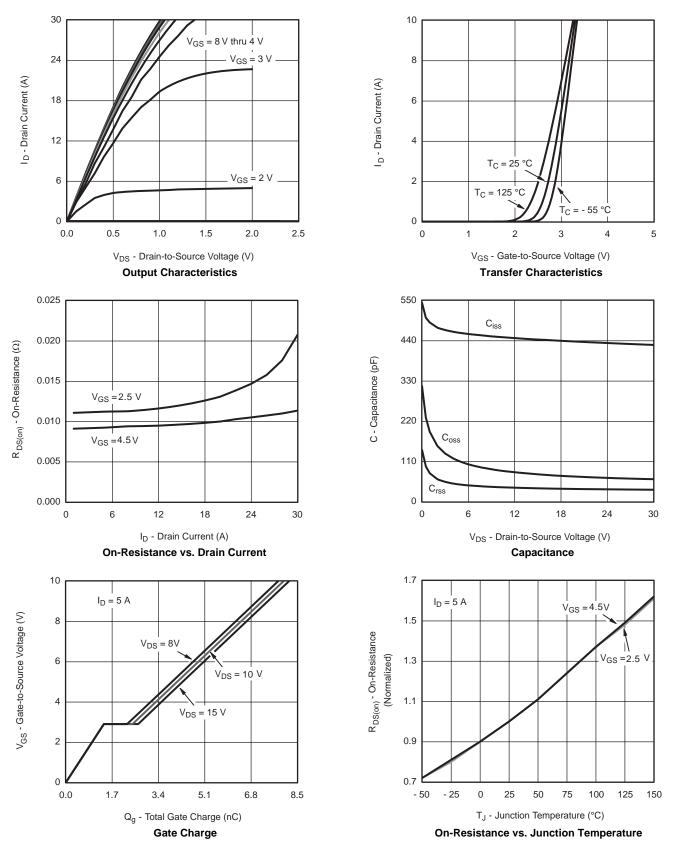
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static					•	•	
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	20			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = 250 μA		32		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = 250 μA		- 5.0			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	0.5		1.0	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 12 \text{ V}$			± 100	nA	
Zana Oata Valta na Brain Oamani		$V_{DS} = 20 \text{ V}, V_{GS} = 0 \text{ V}$	= 0 V		1		
Zero Gate Voltage Drain Current	DSS	V _{DS} = 20 V, V _{GS} = 0 V, T _J = 55 °C			10	μA	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 4.5 \text{ V}$	10			Α	
		$V_{GS} = 4.5 \text{ V} I_{D} = 5 \text{ A}$		0.009		Ω	
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 2.5 \text{ V}, I_D = 4 \text{ A}$		0.012			
Forward Transconductance ^a	g _{fs}	V _{DS} = 10 V, I _D = 5 A	1	16		S	
Dynamic ^b	1						
Input Capacitance	C _{iss}			586			
Output Capacitance	C _{oss}	$V_{DS} = 10V, V_{GS} = 0 V, f = 1 MHz$		117		pF	
Reverse Transfer Capacitance	C _{rss}			55			
		$V_{DS} = 10 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 5 \text{ A}$		15			
Total Gate Charge	Q _g		3.7	5.6	1 _		
Gate-Source Charge	Q _{gs}	$V_{DS} = 10 V$, $V_{GS} = 4.5 V$, $I_{D} = 5 A$		1.4		nC	
Gate-Drain Charge	Q _{gd}			1.05		=	
Gate Resistance	R _g	f = 1 MHz	0.8	4.3	8.6	Ω	
Turn-On Delay Time	t _{d(on)}			12	24		
Rise Time	t _r	$V_{DD} = 10 \text{ V}, R_L = 3 \Omega$		55	100		
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 5 \text{ A}, V_{GEN} = 4.5 \text{ V}, R_g = 1 \Omega$		11	22		
Fall Time	t _f			8	16		
Turn-On Delay Time	t _{d(on)}			4	8	ns	
Rise Time	t _r	$V_{DD} = 10V, R_L = 3 \Omega$		9	18	-	
Turn-Off Delay Time	t _{d(off)}	$I_D \cong 5 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		10	20		
Fall Time	t _f	-		6	12		
Drain-Source Body Diode Characteristi	cs						
Continuous Source-Drain Diode Current	Is	T _C = 25 °C			2.35		
Pulse Diode Forward Current	I _{SM}				24	A	
Body Diode Voltage	V _{SD}	I _S = 2 A, V _{GS} = 0 V		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			11	20	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	L 5 A 41/44 400 A/22 T 05 00		4	8	nC	
Reverse Recovery Fall Time	t _a	$I_F = 5 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 \text{ °C}$		7			
Reverse Recovery Rise Time	t _b	7		4		ns	

Notes:

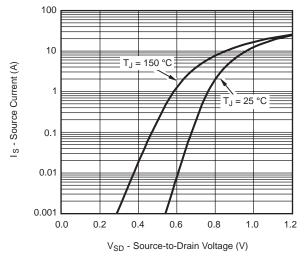
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

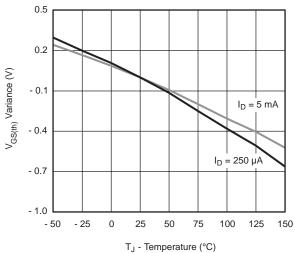




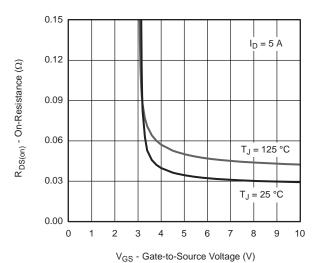




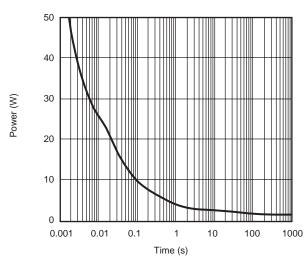
Source-Drain Diode Forward Voltage



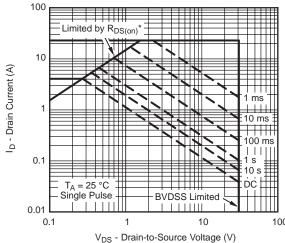
Threshold Voltage



On-Resistance vs. Gate-to-Source Voltage



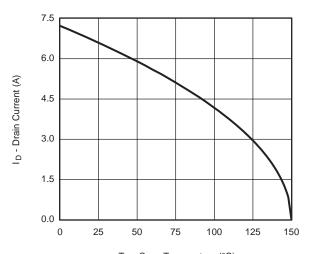
Single Pulse Power



* V_{GS} > minimum V_{GS} at which R_{DS(on)} is specified

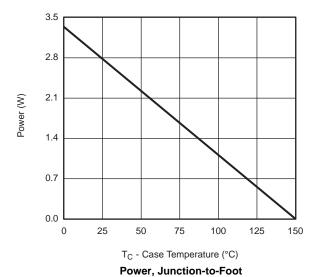
Safe Operating Area, Junction-to-Ambient

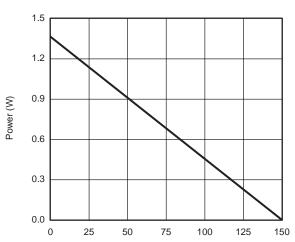




T_C - Case Temperature (°C)





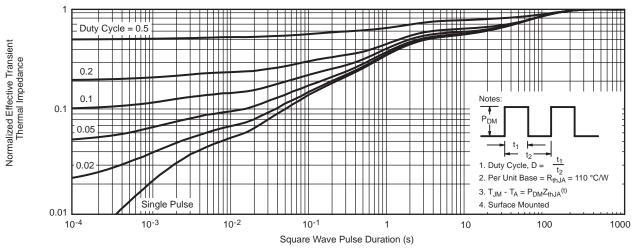


T_A - Ambient Temperature (°C)

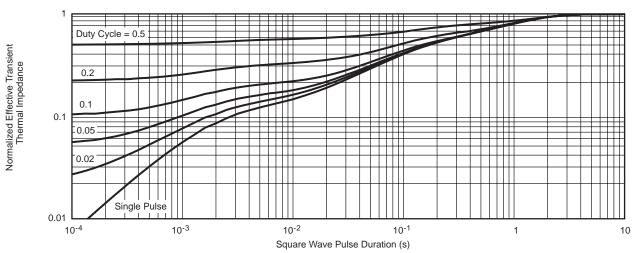
Power, Junction-to-Ambient

^{*} The power dissipation P_D is based on $T_{J(max)} = 150$ °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEAD JEDEC Part Number: MS-012







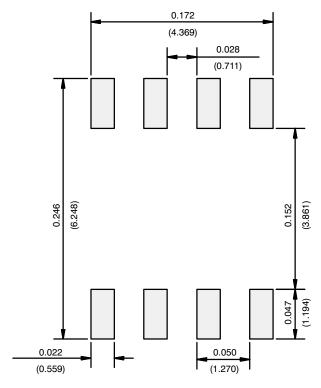
	MILLIN	IETERS	INC	HES		
DIM	Min	Max	Min	Max		
Α	1.35	1.75	0.053	0.069		
A ₁	0.10	0.20	0.004	0.008		
В	0.35	0.51	0.014	0.020		
С	0.19	0.25	0.0075	0.010		
D	4.80	5.00	0.189	0.196		
E	3.80	4.00	0.150	0.157		
е	1.27	BSC	0.050	0.050 BSC		
Н	5.80	6.20	0.228	0.244		
h	0.25	0.50	0.010	0.020		
L	0.50	0.93	0.020	0.037		
q	0°	8°	0°	8°		
S	0.44	0.64	0.018	0.026		
ECN: C-06527-Pay I 11-San-06						

ECN: C-06527-Rev. I, 11-Sep-06

DWG: 5498



RECOMMENDED MINIMUM PADS FOR SO-8



Recommended Minimum Pads Dimensions in Inches/(mm)

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